

Notice of References Cited	Application/Control No. 10/082,563	Applicant(s)/Patent Under Reexamination ISHIDA ET AL.	
	Examiner Qutub Ghulamali	Art Unit 2637	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	Voorakaranam et al, "Low-Jitter Measurement Technique for Phase-Locked loops", Circuits and Systems, 2000. Proceedings of the 43rd IEEE Midwest Symposium on, August 2000, Vol. 2, pages 956-959.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.